

SWITCHING N-CHANNEL POWER MOS FET

DESCRIPTION

NEC

The NP160N04TDG is N-channel MOS Field Effect Transistor designed for high current switching applications.

ORDERING INFORMATION

PART NUMBER	LEAD PLATING	PACKING	PACKAGE	
NP160N04TDG-E1-AY ^{Note}		Tape 800 p/reel		
NP160N04TDG-E2-AY Note	Pure Sn (Tin)		TO-263-7pin (MP-25ZT) typ. 1.5 g	

Note Pb-free (This product does not contain Pb in the external electrode).

FEATURES

- Super low on-state resistance $R_{DS(on)1} = 1.6 \text{ m}\Omega \text{ TYP.} / 2.0 \text{ m}\Omega \text{ MAX.} (V_{GS} = 10 \text{ V}, \text{ ID} = 80 \text{ A})$ $R_{DS(on)2} = 2.2 \text{ m}\Omega \text{ TYP.} / 5.4 \text{ m}\Omega \text{ MAX.} (V_{GS} = 4.5 \text{ V}, \text{ ID} = 80 \text{ A})$
- High Current Rating ID(DC) = ±160 A
- Logic level drive type

ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

Drain to Source Voltage (VGs = 0 V)	VDSS	40	V
Gate to Source Voltage (VDS = 0 V)	Vgss	±20	V
Drain Current (DC) (Tc = 25°C)	D(DC)	±160	А
Drain Current (pulse) ^{Note1}	D(pulse)	±640	А
Total Power Dissipation (Tc = 25°C)	P T1	220	W
Total Power Dissipation (T _A = 25°C)	Pt2	1.8	W
Channel Temperature	Tch	175	°C
Storage Temperature	Tstg	-55 to +175	°C
Single Avalanche Energy Note2	Eas	372	mJ
Repetitive Avalanche Current Note3	IAR	61	А
Repetitive Avalanche Energy Note3	Ear	372	mJ

Notes 1. PW \leq 10 μ s, Duty Cycle \leq 1%

- 2. Starting Tch = 25°C, VDD = 20 V, Rg = 25 $\Omega,$ Vgs = 20 \rightarrow 0 V, L = 100 μH
- **3.** RG = 25 Ω , Tch(peak) \leq 150°C

THERMAL RESISTANCE

Channel to Case Thermal Resistance	Rth(ch-C)	0.68	°C/W
Channel to Ambient Thermal Resistance	Rth(ch-A)	83.3	°C/W

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(TO-263-7pin)

The revised points can be easily searched by copying an "<R>" in the PDF file and specifying it in the "Find what:" field.

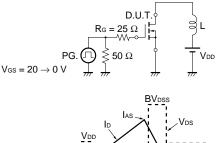
CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	IDSS	V _{DS} = 40 V, V _{GS} = 0 V			1	μA
Gate Leakage Current	lgss	V _{GS} = ±20 V, V _{DS} = 0 V			±100	nA
Gate to Source Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250 μA	1.5	2.0	2.5	V
Forward Transfer Admittance Note	y _{fs}	V _{DS} = 5 V, I _D = 40 A	37	94		S
Drain to Source On-state Resistance Note	RDS(on)1	V _{GS} = 10 V, I _D = 80 A		1.6	2.0	mΩ
	RDS(on)2	V _{GS} = 4.5 V, I _D = 80 A		2.2	5.4	mΩ
Input Capacitance	Ciss	V _{DS} = 25 V,		10500	15750	pF
Output Capacitance	Coss	V _{GS} = 0 V,		980	1470	pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		630	1140	pF
Turn-on Delay Time	td(on)	Vdd = 20 V, Id = 80 A,		35	80	ns
Rise Time	tr	V _{GS} = 10 V,		55	140	ns
Turn-off Delay Time	td(off)	R _G = 0 Ω		107	220	ns
Fall Time	tr			17	50	ns
Total Gate Charge ^{Note}	QG	V _{DD} = 32 V,		180	270	nC
Gate to Source Charge	QGS	V _{GS} = 10 V,		30		nC
Gate to Drain Charge	Qgd	ID = 160 A		57		nC
Body Diode Forward Voltage Note	VF(S-D)	I⊧ = 160 A, V _{GS} = 0 V		0.9	1.5	V
Reverse Recovery Time	trr	I⊧ = 160 A, V _{GS} = 0 V,		49		ns
Reverse Recovery Charge	Qrr	di/dt = 100 A/ <i>µ</i> s		60		nC
	Zero Gate Voltage Drain Current Gate Leakage Current Gate to Source Threshold Voltage Forward Transfer Admittance ^{Note} Drain to Source On-state Resistance ^{Note} Input Capacitance Output Capacitance Reverse Transfer Capacitance Turn-on Delay Time Rise Time Turn-off Delay Time Fall Time Total Gate Charge ^{Note} Gate to Source Charge Gate to Drain Charge Body Diode Forward Voltage ^{Note} Reverse Recovery Time	Zero Gate Voltage Drain CurrentIDDSSGate Leakage CurrentIGSSGate to Source Threshold VoltageVGS(th)Forward Transfer Admittance Note yfs Drain to Source On-state Resistance NoteRDS(on)1Ros(on)2Input CapacitanceCissOutput CapacitanceCossReverse Transfer CapacitanceCrrssTurn-on Delay Timeta(on)Rise TimetrTurn-off Delay Timeta(off)Fall TimetrTotal Gate Charge NoteQGGate to Source ChargeQGDBody Diode Forward Voltage NoteVF(S-D)Reverse Recovery Timetr	Zero Gate Voltage Drain CurrentIbss $V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}$ Gate Leakage CurrentIass $V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$ Gate to Source Threshold Voltage $V_{GS}(th)$ $V_{DS} = V_{GS}, Ib = 250 \mu$ AForward Transfer Admittance Note $ y_{15} $ $V_{DS} = 5 \text{ V}, Ib = 40 \text{ A}$ Drain to Source On-state Resistance Note $R_{DS(on)1}$ $V_{GS} = 10 \text{ V}, Ib = 80 \text{ A}$ Input Capacitance C_{Iss} $V_{DS} = 25 \text{ V},$ Output Capacitance C_{oss} $V_{CS} = 0 \text{ V},$ Reverse Transfer Capacitance C_{rss} $f = 1 \text{ MHz}$ Turn-on Delay Time $t_{d(on)}$ $V_{DD} = 20 \text{ V}, Ib = 80 \text{ A},$ Rise Time t $V_{CS} = 10 \text{ V},$ Fall Time t $V_{CS} = 10 \text{ V},$ Gate to Source Charge Q_{G} $V_{DD} = 32 \text{ V},$ Gate to Drain Charge Q_{GD} $I_{D} = 160 \text{ A}.$ Body Diode Forward Voltage Note $V_{F(S-D)}$ $I_F = 160 \text{ A}, V_{GS} = 0 \text{ V},$	Zero Gate Voltage Drain CurrentIbssVbs = 40 V, Vos = 0 VGate Leakage CurrentIassVas = ± 20 V, Vbs = 0 V1Gate to Source Threshold VoltageVos (Vbs = Vas, Ib = 250μ A1.5Forward Transfer Admittance NoteI yrs IVbs = 5 V, Ib = 40 A37Drain to Source On-state Resistance NoteRbs(on)1Vas = 10 V, Ib = 80 A37Input CapacitanceCissVas = 4.5 V, Ib = 80 A1Input CapacitanceCissVas = 4.5 V, Ib = 80 A1Input CapacitanceCossVas = 25 V,1Output CapacitanceCossVas = 0 V,1Turn-on Delay Timeta(on)Vbb = 20 V, Ib = 80 A,1Turn-off Delay Timeta(on)Vas = 10 V,1Total Gate Charge NoteQasVas = 10 V,1Gate to Source ChargeQasVas = 10 V,1Gate to Drain ChargeQasVas = 10 V,1Body Diode Forward Voltage NoteVr(s-b)Ir = 160 A, Vas = 0 V,1Reverse Recovery TimeVasIs = 160 A, Vas = 0 V,1Reverse Recovery TimeVasIs = 160 A, Vas = 0 V,1Reverse Recovery TimeVasIs = 160 A, Vas = 0 V,1Reverse Recovery TimeVasIs = 160 A, Vas = 0 V,1Reverse Recovery TimeVasIs = 160 A, Vas = 0 V,1Reverse Recovery TimeVasIs = 160 A, Vas = 0 V,1Reverse Recovery TimeVasIs = 160 A,	Zero Gate Voltage Drain CurrentIossVos = 40 V, Vos = 0 VImage: Constant of the second state of the sec	Zero Gate Voltage Drain Current Ioss Vbs = 40 V, Vas = 0 V Image: Margin Current I

ELECTRICAL CHARACTERISTICS (TA = 25°C)

Note Pulsed test

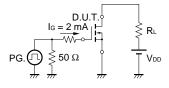
TEST CIRCUIT 1 AVALANCHE CAPABILITY

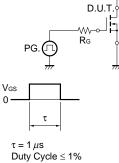
TEST CIRCUIT 2 SWITCHING TIME

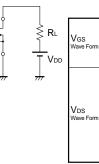


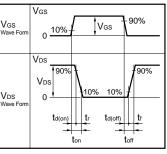
Starting T_{ch}

TEST CIRCUIT 3 GATE CHARGE

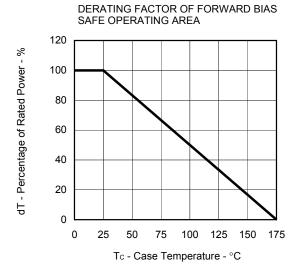




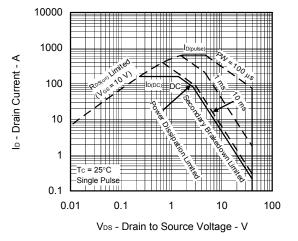


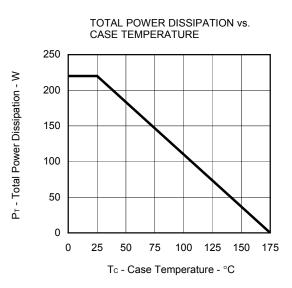


TYPICAL CHARACTERISTICS (TA = 25°C)

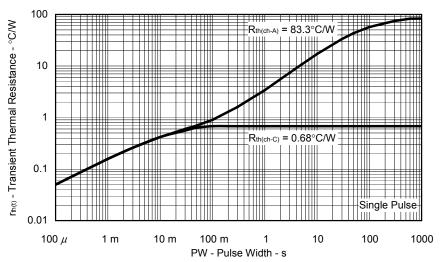




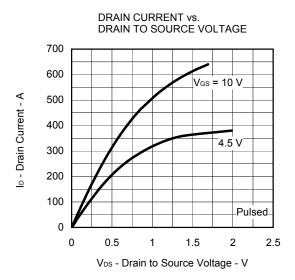




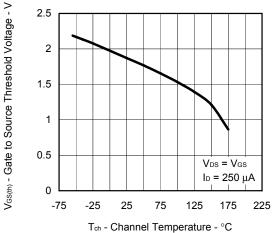
TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH



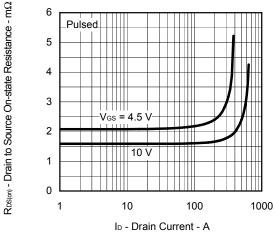
Data Sheet D18761EJ2V0DS



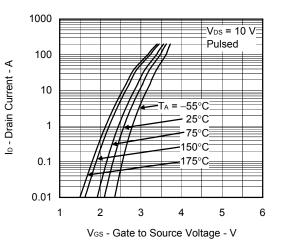




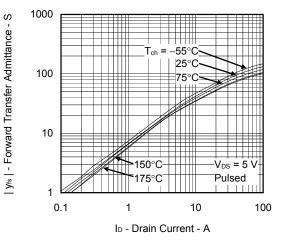




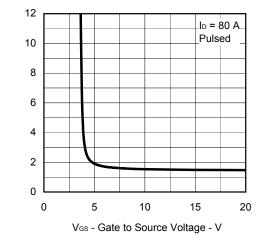
FORWARD TRANSFER CHARACTERISTICS



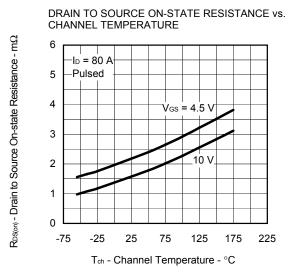
FORWARD TRANSFER ADMITTANCE vs. DRAIN CURRENT



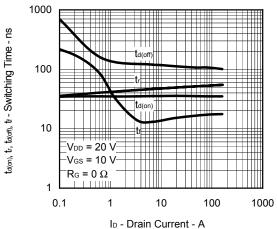


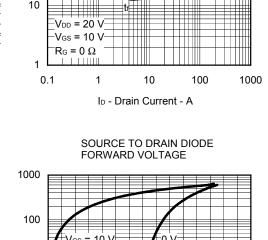


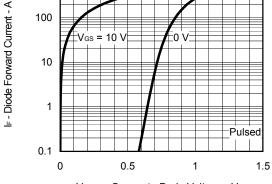
 $R_{DS(cn)}$ - Drain to Source On-state Resistance - $m\Omega$





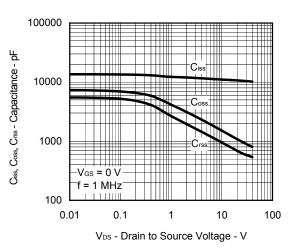




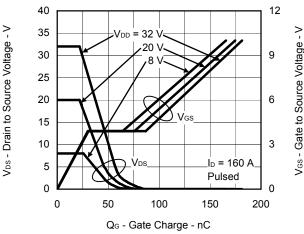


V_{F(S-D)} - Source to Drain Voltage - V

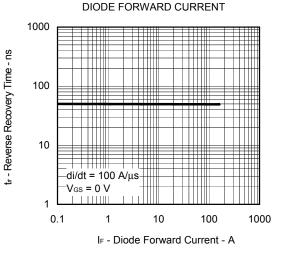
<R> CAPACITANCE vs. DRAIN TO SOURCE VOLTAGE



DYNAMIC INPUT/OUTPUT CHARACTERISTICS

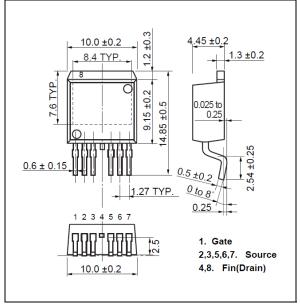


REVERSE RECOVERY TIME vs.

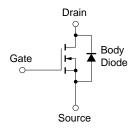


PACKAGE DRAWING (Unit: mm)

TO-263-7pin (MP-25ZT)



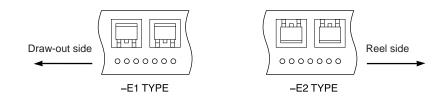
EQUIVALENT CIRCUIT



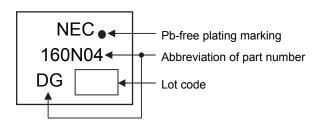
Remark Strong electric field, when exposed to this device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it once, when it has occurred.

TAPE INFORMATION

There are two types (-E1, -E2) of taping depending on the direction of the device.



MARKING INFORMATION



RECOMMENDED SOLDERING CONDITIONS

The NP160N04TDG should be soldered and mounted under the following recommended conditions.

For soldering methods and conditions other than those recommended below, please contact an NEC Electronics sales representative.

For technical information, see the following website.

Semiconductor Device Mount Manual (http://www.necel.com/pkg/en/mount/index.html)

Soldering Method	Soldering Conditions	Recommended Condition Symbol	
Infrared reflow	Maximum temperature (Package's surface temperature): 260°C or below		
	Time at maximum temperature: 10 seconds or less		
	Time of temperature higher than 220°C: 60 seconds or less		
	Preheating time at 160 to 180°C: 60 to 120 seconds	IR60-00-3	
	Maximum number of reflow processes: 3 times		
	Maximum chlorine content of rosin flux (percentage mass): 0.2% or less		
Partial heating	Maximum temperature (Pin temperature): 350°C or below		
	Time (per side of the device): 3 seconds or less	P350	
	Maximum chlorine content of rosin flux: 0.2% (wt.) or less		

Caution Do not use different soldering methods together (except for partial heating).

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